



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS ANNOUNCES DEVELOPMENT ORDER FOR
300mm FULL WAFER CONTACT TESTER**

FREMONT, CA. (June 19, 2002) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of test and burn-in equipment to semiconductor manufacturers, today announced the receipt of an order totaling over \$2 million dollars for engineering development of a full wafer contact test system. The system will be developed using proprietary interconnect and parallel test technology currently utilized in Aehr Test Systems' full wafer contact FOX™ product line.

The full wafer contact system is expected to parallel test 200mm and 300mm wafers. One of the system's powerful features will provide individual DUT power supplies using proven MTX test technology. C.J. Meurell, president and chief operating officer of Aehr Test said, "A DFT or JTAG test strategy eliminates many of the barriers to full wafer contact and allows for an extremely cost effective test solution. Testing an entire wafer of die at the same time certainly changes the dynamics of manufacturing test costs and throughput improvements."

Many semiconductor device manufacturers have recognized that a design for test (DFT) strategy can increase productivity and greatly reduce manufacturing test costs. This semiconductor design strategy combined with contact and test technologies that can allow full wafer contact and test creates a new paradigm in the semiconductor backend process. "We are very excited about this order," says Rhea Posedel, Chairman and CEO, "It expands our FOX family of products and positions us into new growing markets."

This development project includes performance milestones which are scheduled to be completed during calendar 2002 and 2003. Non-recurring engineering (NRE) revenue will be recorded as earned, upon milestone completion.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems and the DiePak® carrier. The FOX is a full wafer contact burn-in and test



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system. The MTX is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX systems can effectively burn-in and functionally test sophisticated devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for the Company's products. Actual results may vary from projected results. These risks and uncertainties include economic conditions in Asia and elsewhere, world events, acceptance by customers of the MTX, MAX and DiePak technologies, the Company's development and manufacture of a commercially successful wafer-level burn-in system, the Company's ability to meet engineering milestones, and the potential emergence of alternative technologies, which could adversely affect demand for the Company's products in fiscal year 2003. See the Company's latest 10-K and 10-Q reports filed with the SEC for additional risks affecting the Company.

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